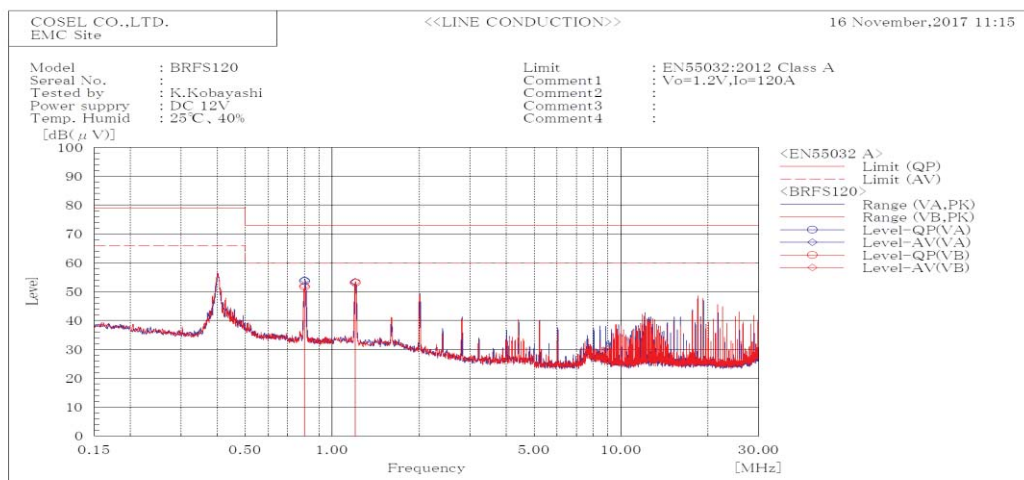
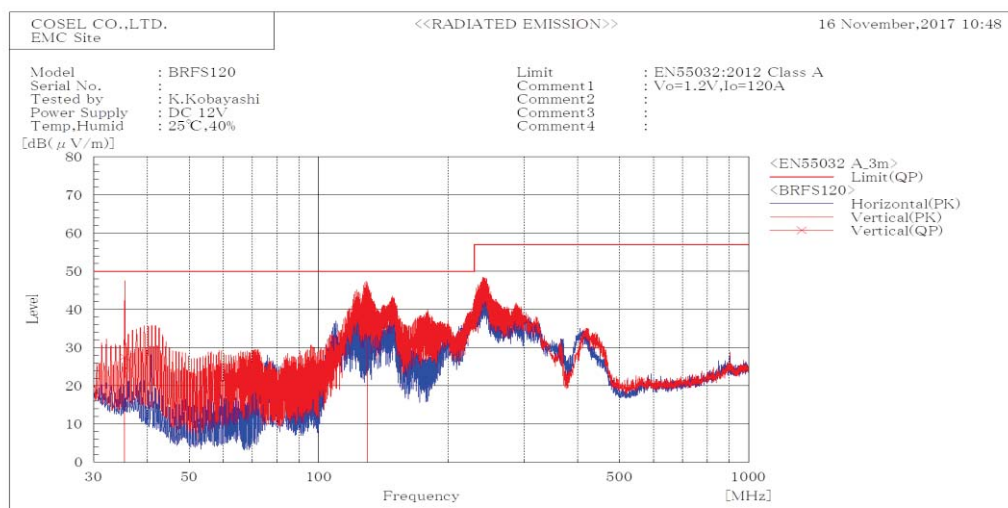


DATA SHEET		Date	18-Dec-17
Model	BRFS120	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi



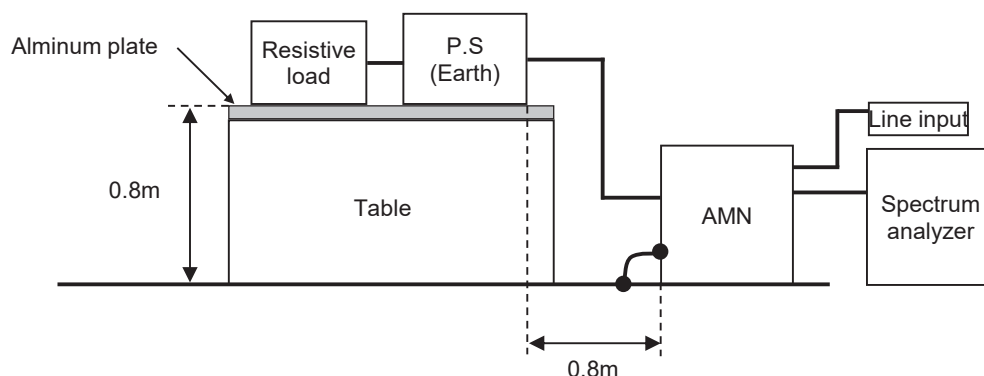
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.80134	VB	51.8	52	73	60	21.2	8	Pass	
0.80187	VA	53.8	54	73	60	19.2	6	Pass	
1.20201	VB	53.1	53.4	73	60	19.9	6.6	Pass	
1.20286	VA	53.2	53.4	73	60	19.8	6.6	Pass	



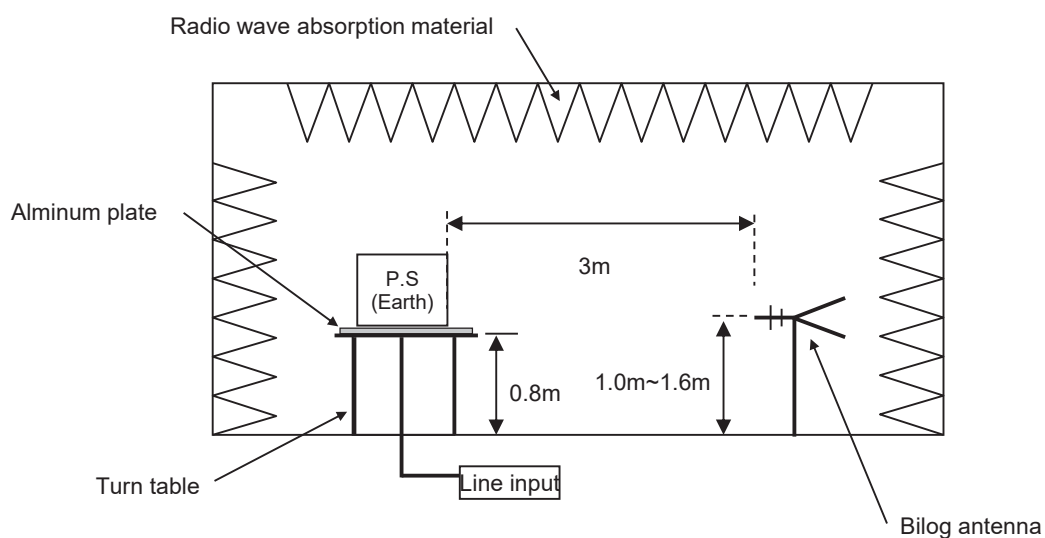
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
35.315	V	Stable	27.5	50.0	22.5	Pass	105	329	
129.615	V	Stable	43.6	50.0	6.4	Pass	106	27	

DATA SHEET		Date	18-Dec-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Kobayashi

1. Line conduction



2. Radiated emission



Conditions

Test : EMI
Model Name : BRFS120

○Photographs of Test Set-Up

LINE CONDUCTION

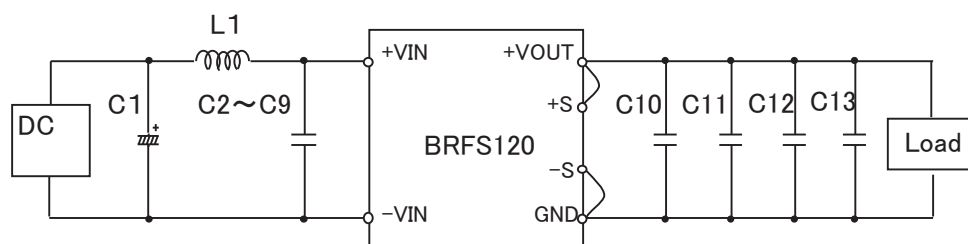


RADIATED EMISSION



○Testing circuitry

○Test Circuit



C1	: 25V	470 μ F	Electrolytic capacitor
C2~C9	: 16V	22 μ F	Ceramic capacitor
C10~C13	: 6.3V	100 μ F	Ceramic capacitor
L1	: 0.3 μ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)